AI and ML in the Future of Wearable Devices

Guest Editor:

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closed (30 June 2022)

Message from the Guest Editor

Dear Colleagues,

Wearable industry will experience an enormous boom in the near future, and it aims to influence the fields of health and medicine, aging, disability, and gaming, among others.

The aim of this Special Issue is to seek high-quality contributions that highlight methodologies, applications, and algorithms of machine learning for wearable devices. Surveys of the state-of-the-art are also welcomed. Topics of interest include but are not limited to the following:

- Wearable technology and gaming;
- Clothing technology;
- Monitoring systems for assisted living;
- Intelligent algorithms that are able to infer information from collected data;
- Statistical classification methods;
- Neural networks;
- Deep learning;
- Technology to integrate into textiles;
- Smart connected things;
- Wearable simulation.

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Special Issue

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Message from the Editor-in-Chief

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